

Received August 22, 2019, accepted September 11, 2019, date of publication September 18, 2019, date of current version October 3, 2019.

Digital Object Identifier 10.1109/ACCESS.2019.2942150

Combination-Encoding Content-Addressable Memory With High Content Density

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This work was supported by the research grant of the National Research Foundation of Korea under Grant NRF-2019R1C1C1009810.

ABSTRACT Recently, resistance switch-based content-addressable memory (RCAM) has been proposed as an alternative to the mainstream static random-access memory-based CAM because of its high integration potential and low static energy consumption. However, RCAM has a lower data density due to the use of a pair of resistance switches for a single bit of contents (0.5 bit/switch) than resistive random access memory (1 bit/switch). In this paper, we propose a new type of RCAM referred to as combination-encoding CAM (CECAM). In the N-CECAM, a single unit consists of N high and N low resistance state switches whose combination collectively represents binary contents, yielding a data density of approximately 0.85 bit/switch when N = 10, for instance. The key to the CECAM is the encoding of an n-bit search key as a 2N-digit key and its decoding. To this end, we propose a simple algorithm for encoding and decoding and its implementation in digital circuitry.

INDEX TERMS Content-addressable memory, combination-encoding content-addressable memory, resistance switch, crossbar array, content density.

I. INTRODUCTION

Content-addressable memory (CAM) is a type of memory accessed based on contents instead of memory addresses as opposed to random access memory (RAM) [1]. Upon receiving an input data word to search (search key), CAM simultaneously searches all memory entries for search-keyrelevant contents in one clock cycle and returns the addresses of the contents. Therefore, CAM has a significant advantage over RAM in searching speed. Its main application domains include lookup tables (LUTs) in network routers [2]-[7]. The network router decides the forwarding direction of a data packet between networks. The LUT in the network router including the hierarchical addresses is searched for the best route or port for the data packet to be forwarded. Additionally, the CAM storing the LUT is a critical component for digital communications among neurons in neuromorphic hardware [8]. The LUT including the topology of a neural network is searched for the postsynaptic neuron addresses

The associate editor coordinating the review of this manuscript and approving it for publication was Yue Zhang.

upon the occurrence of an event from a presynaptic neuron. A fast search of the CAM significantly accelerates event routing processes, enabling real-time inference and learning. It also applies to vector-quantization [9], decomposing an input image to a set of vectors, and information retrieval [10], finding the information relevant to the desired information from big data.

CAM is categorized as binary CAM (BCAM) and ternary CAM (TCAM). As the names indicate, each unit cell in BCAM represents either '0' or '1' whereas that in TCAM has an additional 'don't care' (or 'X') state [1]. For instance, '1X1' in TCAM is matched to search keys '101' and '111' because 'X' matches both '0' and '1'. This high flexibility of TCAM is the key to packet forwarding tasks [2]–[7].

Static RAM (SRAM)-based CAM is the most popular form of CAM [1], [11]. The SRAM-based CAM leverages fast searching speed and high compatibility with well-established complementary metal-oxide-semiconductor (CMOS) technologies. Nevertheless, significant disadvantages are its low areal density due to the use of many transistors (≥ 8) to represent a single bit and high static power consumption

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due to the leakage current of SRAM [12]–[14]. As alternatives to the SRAM-based CAM, CAMs based on emerging non-volatile memories (NVMs) such as phase-change memory [14]–[16], magnetic tunnel junction [14], [17]–[19], ferroelectric memory [20], and resistance switch [21]–[25] have been proposed to date. Such NVM-based CAMs highlight their high data density and zero-static energy consumption due to the non-volatility. They also offer solutions to TCAM by appropriately configuring the non-volatile memory elements [14]–[25].

Among candidates, switch-based the resistance CAM (RCAM) is a front runner; two-transistor two-resistor (2T2R)-based RCAM has been prototyped using a 4 kb resistive RAM (RRAM) [25]. Additionally, RCAM may be realized in a passive crossbar array that highlights its ideal $8F^2$ cell size [21], [23]. Nevertheless, RCAM has a lower content density than RRAM because it uses a pair of resistance switches as a single bit of content, i.e., 0.5 bit/switch. A further increase in data density needs a new content-encoding framework. To this end, we propose a new type of resistance switch-based CAM, named combination-encoding CAM (CECAM).

Section II outlines the working principle of the CECAM including a search key-encoding algorithm (Section II.A) and its implementation in a digital circuit (Section II.B). Section III explains parallel searches of multiple CECAM domains to realize TCAM with coarse granularity. Reading contents from the CECAM needs to decode them using an appropriate decoding algorithm because the contents in the CECAM are encoded, which is addressed in Section IV. Finally, Section V highlights the general application of the CECAM scheme to various CAM designs.

II. COMBINATION-ENCODING CONTENT-ADDRESSABLE MEMORY

Fig. 1 illustrates a schematic of unit cells of active and passive RCAMs (voltage- and current-reading schemes, respectively). RCAM takes a pair of resistance switches as a single unit of single-bit capacity. Each switch is set to one of the binary states: high resistance state (HRS) and low resistance state (LRS). Specifically, the two switches are complementary; they are in different resistance states. This yields two distinguishable configurations, HRS-LRS (HL) and LRS-HRS (LH), representing one bit of content. For both schemes in Fig. 1, LH corresponds to '0' and HL to '1'. Each bit of a search key is represented by voltage signals on complementary search lines (SL and \overline{SL}) such that '0' pulls SL low and SL high while '1' pulls SL high and SL low. When a search bit of '0' is applied to a stored content of '0' (LH), the RCAM units in Figs. 1a and 1b notify matching signals on the match lines (black $V_{\rm ML}$ and $I_{\rm ML}$ in Figs. 1c and 1d, respectively). These signals are contrasted with a mismatching case, where a search bit of '1' is applied to the same content '0', resulting in mismatch signals on the match lines indicated by the red $V_{\rm ML}$ and $I_{\rm ML}$ in Figs. 1c and 1d,

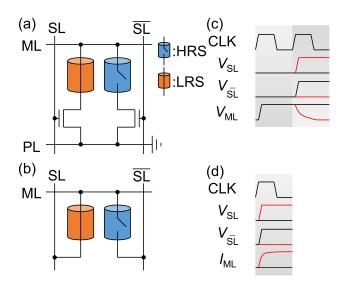


FIGURE 1. Schematic of the conventional RCAM in (a) active and (b) passive crossbar arrays. ML, SL, SL, and PL denote a match line, search line, complementary search line, and plate line, respectively. A timing diagram for active and passive arrays is illustrated in (c) and (d), respectively. CLK, $V_{\rm SL}$, $V_{\rm SL}$, and $V_{\rm ML}$ denote a clock cycle, search line voltage, complementary search line voltage, and match line voltage, respectively. $I_{\rm ML}$ in (d) means the current through the match line. The red lines in (c) and (d) indicate $V_{\rm SL}$, $V_{\rm SL}$, and the CAM responses when mismatching.

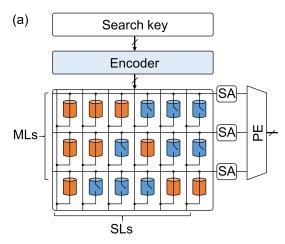
respectively. Thus, searching *N*-bit keys commonly needs 2*N* switches per match line, i.e., 0.5 bit/switch per match line.

In contrast, N-CECAM (N = 1, 2, 3, ...) uses a chunk of 2N switches per match line as a single unit of multi-bit capacity, boosting the memory capacity per switch far beyond a content density of 0.5 bit/switch. Its key difference from RCAM is that the *N*-CECAM harnesses the large number of possible combinations of 2N switches to boost the content density in contrast to RCAM using complementary pairs of switches and search lines to store and search a single bit of contents. We regard a passive array of nonvolatile resistance switches with current reading as a model system of the CECAM. This model system leverages its high memory density and fast content reading. Nevertheless, the sneak current disturbing current read-out processes is a critical downside. However, the CECAM concept is fully compatible with other types of CAM including active arrays of resistance switches freer from the sneak current issue, which will be addressed in Section V.

The N-CECAM consists of a resistance switch array and a search key encoder as illustrated in Fig. 2(a). In the array, 2N resistance switches are placed at the crossing points between each match (horizontal) line and 2N search (vertical) lines. The search key encoder converts an n-bit search key to a 2N-digit binary key, and each digit is applied to each of the 2N search lines such that '1' and '0' pull the search line high and low, respectively. Assuming m switches are in the HRS and the other (2N-m) switches in the LRS, the minimum current response to a single 2N-digit binary key exists only if the key includes m 1's and (2N-m) 0's, and each of the m 1's in the key is matched to each of the m HRS switches.

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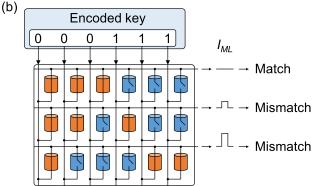


FIGURE 2. (a) Schematic of 3-CECAM (N=3). A single unit consists of N HRS and N LRS switches. SA and PE mean a sense amplifier and priority encoder, respectively. (b) Current responses to a given encoded key upon a match and mismatches. Matching allows the minimal current response (first row).

To maximize the number of possible configurations of 2N switches $\binom{2N}{m}$, m is set to N. Thus, the search key encoder maps an n-bit search key to a 2N-digit key with N 1's and N 0's in a bijective manner. When matching N 1's in the encoded key to the N HRS switches, the current response through the match line is minimal as shown in Fig. 2(b). Otherwise, some 1's in the encoded key are inevitably associated with LRS switches, and thus the current response through the match line becomes high, indicating a mismatch. Note that the current response scales with the degree of mismatch, i.e., the number of mismatched bits in the encoded key. The worst mismatch regarding a sensing margin is due to two mismatched bits as depicted in Fig. 2(b).

The total number of 2N-digit encoded keys is $\binom{2N}{N}$, and so is the number of 2N switch configurations per match line. Given the use of n-bit search keys, 2^n of $\binom{2N}{N}$ configurations are associated with the total n-bit keys, satisfying $2^n \le \binom{2N}{N} < 2^{n+1}$. This inequality yields

$$n = \left\lfloor \log_2 \binom{2N}{N} \right\rfloor \tag{1}$$

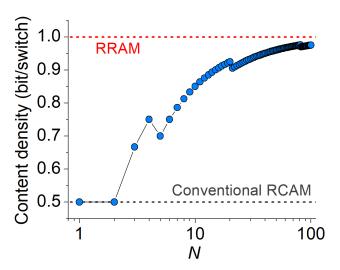


FIGURE 3. Content density of *N*-CECAM with *N* in comparison with the conventional RCAM and RRAM. The kinks arise from the floor function in (1).

where $\lfloor \cdot \rfloor$ denotes a floor function. Therefore, the content density (content bit per switch) is given as $\log_2 \binom{2N}{N} / 2N$, which is plotted in Fig. 3. Notably, for N's (>2), the content density exceeds the density of the conventional RCAM designs (0.5 bit/switch) and approaches the density of RRAM (1 bit/switch) asymptotically.

A. ALGORITHM FOR COMBINATION ENCODING

The key to the *N*-CECAM is the bijective mapping of the total *n*-bit search keys to 2^n 2N-digit keys $(2^n \le \binom{2N}{N}) \le 2^{n+1}$) using an appropriate encoding function. We propose the encoding function E_N for an *n*-bit search key a as follows:

function $E_N(a)$ **set** b **to** 2N-digit binary number 0 **for** i=0 **to** N-1 **do if** there is c satisfying $\binom{c}{N-i} \leq a < \binom{c+1}{N-i}$ **then set** the (c+1)th digit of b **to** 1 **set** a **to** $a-\binom{c}{N-i}$ **end if end for return** b

Note that E_N is bijective when $A_t = \left\{0, 1, \dots, \binom{2N}{N} - 1\right\}$ and $B_t = \{b \mid b: 2N$ -digit binary numbers with of N 1's and N 0's are taken as the domain and codomain of E_N , respectively (**Theorem 1** in Appendix). Therefore, E_N is also a bijective function for domain $A = \{0, 1, \dots, 2^n - 1\}$ ($\subset A_t$) and codomain $B = \{E_N(0), E_N(1), \dots, E_N(2^n - 1)\}$ ($\subset B_t$).

Table 1 shows the encodings of 4-bit search keys as 16 distinguishable 6-digit binary numbers with three 1's and three 0's using the encoding function E_3 (N=3). The encoded

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end function.



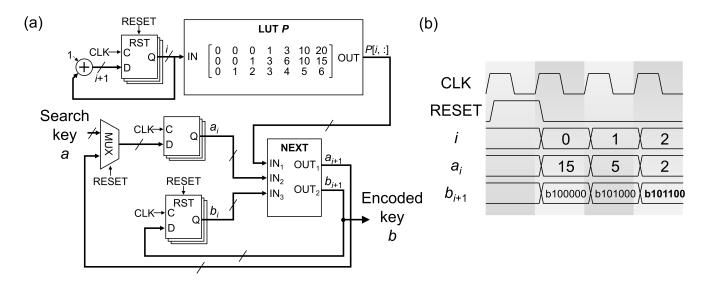


FIGURE 4. (a) Block diagram of an encoding circuit for 3-CECAM. (b) Timing diagram for encoding a search key of 15 as a 6-digit key of 101100.

data are subsequently programmed in 2N switches such that a '1' and '0' in the encoded data are written as 'H' and 'L', respectively. 'H' and 'L' denote HRS and LRS, respectively. The last configuration 'HHHHHHH' indicates 'don't care' for TCAM.

A search key is encoded as a 2N-digit key iteratively, which

B. IMPLEMENTATION OF ENCODING CIRCUIT

needs to be implemented in circuitry in a way to reduce a delay in decoding at the cost of memory usage. To this end, for $0 \le c \le 2N$ and $0 \le i < N$ is stored in a memory, which is referred to as a combination table. The LUT P is an $N \times (2N+1)$ matrix whose element A main advantage of employing the combination table is that the comparison $\binom{c}{N-i} \leq a < c$ $\binom{c+1}{N-i}$ in the encoding function $E_{\rm N}$ can be accelerated considerably by retrieving $\binom{c}{N-i}$ and $\binom{c+1}{N-i}$ from the LUT P rather than evaluating them for every comparison. A block diagram of the encoding circuit including the LUT P is shown in Fig. 4(a). When RESET is 1, the encoding circuit receives search key a that is encoded (a_0) . Simultaneously, a 2N-long array b is initialized as $b_0[k] = 0$ for $0 \le k <$ 2N, where $b_0[k]$ denotes the (k+1)th digit of b_0 . We note that RESET is synchronized with clock signals (CLK) to avoid a metastability problem as shown in Fig. 4(b). The circuit first addresses the first row of the LUT P, i.e., P[0,:]. The NEXT block finds c in P[0,:], satisfying $P[0,c] \le a_0 <$ P[0,c+1], using parallel comparators, resulting in c_0 . a_1 is consequently evaluated as $a_1 = a_0 - P[0, c_0]$. b_1 is identical to b_0 except its (c_0+1) th digit that is set to one, $b_1[c_0] = 1$. c_1 is subsequently evaluated for the next row of the LUT P,

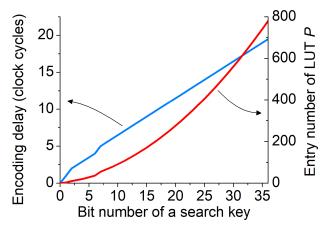


FIGURE 5. Encoding delay and number of entries in the LUT P with the bit number of a search key (n).

i.e., P[1, :], as for the first row. This evaluation is repeated for all remaining rows, eventually resulting in a 2N-digit encoded key $b = b_N$. Therefore, the delay in encoding is caused by iteratively addressing each row of the LUT P, which scales with N(Fig. 4(b)). Given the relationship in (1), the encoding delay is associated with the bit number of a search key (n) as plotted in Fig. 5 (blue line); the delay tends to increase with the bit number. To address the memory overhead for the LUT P, the number of its entries was also evaluated with the bit number of a search key and co-plotted in Fig. 5 (red line).

III. PARALLEL SEARCH OF N-CECAM DOMAINS

A search of a single N-CECAM domain can be extended to parallel searches of multiple N-CECAM domains (partitions). Such parallel searches are useful, particularly, when a search key is so lengthy that N becomes large according to (1). To this end, $n_{\rm p}$ partitions are given to each match line, where each partition is a single $N_{\rm p}$ -CECAM domain loaded

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Integer	Configuration	Search key	Integer	Configuration	Search key
0	LLLHHH	000111	9	LHHHLL	011100
1	LLHLHH	001011	10	HLLLHH	100011
2	LLHHLH	001101	11	HLLHLH	100101
3	LLHHHL	001110	12	HLLHHL	100110
4	LHLLHH	010011	13	HLHLLH	101001
5	LHLHLH	010101	14	HLHLHL	101010
6	LHLHHL	010110	15	HLHHLL	101100
7	LHHLLH	011001	0 – 15	НННННН	000000
8	LHHLHL	011010			

TABLE 1. Truth table of encodings of 4-bit integers as resistor configurations (N=3).

with $2N_{\rm p}$ resistance switches in total. All partitions can share a single LUT P whose component P[i, c] is $\binom{c}{N_{\rm p}-i}$ for $0 \le c \le 2N_{\rm p}$ and $0 \le i < N_{\rm p}$ as in Fig. 6. Therefore, each match line holds n bits expressed as

$$n = \left\lfloor \log_2 \left(\frac{2N_{\rm p}}{N_{\rm p}} \right) \right\rfloor \cdot n_{\rm p}. \tag{2}$$

Each of n_p partitions is responsible for each n/n_p bit chunk of the total n-bit search key. Notably, this method reduces content-memory density. For instance, for a 60-bit search key, $n_p = 1, 4, 10, 15,$ and 60 (respectively corresponding to $N_p = 32, 9, 4, 3, \text{ and } 1)$ yields approximately 0.94, 0.83, 0.75, 0.67, and 0.5 bit/switch, respectively. $N_p = 32$ and 1 indicate the single domain CECAM and the conventional 2R-based RCAM, respectively. Despite the reduction in content density, the advantage of the partitioning is threefold: reductions in the encoding delay and memory usage for the LUT P, and granularity of 'don't care' bits. Regarding the first advantage, the encoding delay is proportional to N_p as considered in Section II.B. Therefore, reducing $N_{\rm p}$ results in a reduction in the encoding delay. Regarding the second advantage, the LUT P is an $N_p \times (2N_p+1)$ matrix where the largest component is $\binom{2N_p}{N_p}$ which reaches 1.83×10^{18} for $N_p = 1$, requiring 61-bit memory. Thus, reducing $N_{\rm p}$ (i.e., introducing partitions) reduces memory usage for the LUT P considerably.

For TCAM application, a configuration of All $2N_p$ resistance switches in the HRS represents 'don't care' bits in an N_p -CECAM domain. Therefore, the granularity of 'don't care' bits in the N_p -CECAM equals n/n_p bits. As shown in Table 1, 3-CECAM offers a 'don't care' granularity of 4 bits; when all six resistance switches in a domain are set to the HRS, the switch configuration is matched to any of 4-bit search keys between 0 and 15. Setting $N_p = 32$ for 60-bit search keys yields the coarsest granularity (60 bits), unsuitable for TCAM applications whereas $N_p = 1$, equivalent to the conventional RCAM, yields the finest granularity (1 bit). Therefore, introducing partitions is a viable method to decrease data granularity. Nevertheless, because this comes

at the cost of a reduction in content density, the granularity should be reconciled with content density.

IV. ALGORITHM FOR CONTENT DECODING AND CIRCUIT IMPLEMENTATION

Contents in the state-of-the-art 2T2R-RCAM illustrated in Fig. 1(a) are read bitwise such that each bit (a pair of resistance switches) is iteratively examined for matching with the same key applied to the complementary search lines (SL and $\overline{\text{SL}}$) [14]. Therefore, a delay in reading is proportional to the bit number of contents. An advantage of a passive array of resistance switches shown in Fig. 1(b) over the active array is that the total contents per match line can simultaneously be read by pulling the match line high and simultaneously measuring the current response on all search lines. Either design employing the CECAM should be able to decode the 2N-digit contents as the original n-bit contents by an appropriate decoding function. The decoding function D_N is the reverse of the encoding function E_N , which is implemented as follows:

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function D_N(b)

set a, i, c to 0

while i < N do

if [the (c+1)th 	ext{ digit of } b] = 1 then

set i to i+1

set a to a + {c \choose i}

end if

set c to c+1

end while

return a

end function.
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A 2N-digit content in the CECAM is decoded as an *n*-bit key iteratively.

The decoding function D_N is implemented in a digital circuit as shown in Fig. 7(a). The circuit first initializes an n-long array a_0 to 0. Upon receiving a 2N-digit content b that is decoded ($b = b_0$), the ADR block in Fig. 7(a) searches for the address of the right-most '1' in b_0 and returns it,



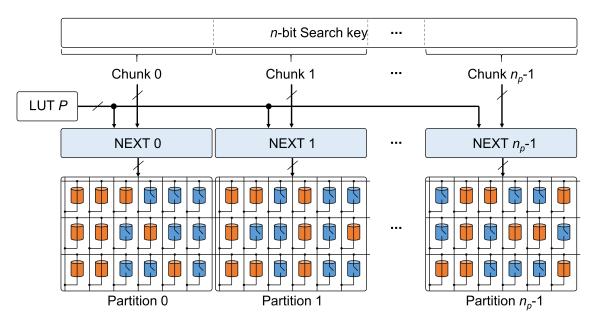


FIGURE 6. Schematic of parallel searches of N_p -CECAM partitions. NEXT in the figure means NEXT block in the encoding circuit. The n-bit search key is divided into n_p chunks, and each chunk applies to the NEXT block of each partition. All partitions share a single LUT P.

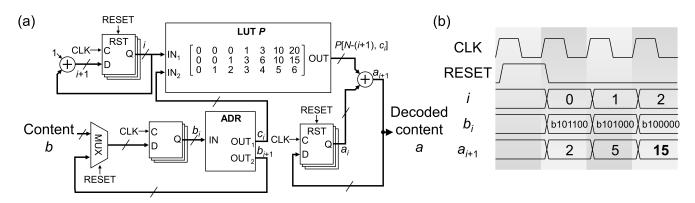


FIGURE 7. (a) Block diagram of a decoding circuit for 3-CECAM. (b) Timing diagram for decoding an encoded search key of 101100 as its original search key (15).

which corresponds to $c_0(b_0[c_0] = 1)$. $P[N-1,c_0] = \binom{c_0}{1}$ is subsequently retrieved from the LUT P, and a_1 is evaluated as $a_1 = a_0 + P[N-1, c_0]$. b_1 is identical to b_0 other than its right-most '1' switched to '0'. Subsequently, c_1 is evaluated as the address of the right-most 1 in b_1 , and then a_2 and b_2 are evaluated as $a_2 = a_1 + P[N-2, c_1]$ and $b_2 = b_1$ except that $b_2[c_1] = 0$, respectively. This evaluation is repeated N times, resulting in an n-bit decoded content a. Similar to encoding, a delay in decoding is caused by iteratively addressing each row of the LUT P. Therefore, the delay also scales with N(Fig. 7(b)).

V. DISCUSSION

The CECAM scheme was applied to a passive array of resistance switches as a model system. This model system allows the ultimate integration density, i.e., when used as RAM, 4F² cell size per bit. In this case, a current-sensing

scheme is suitable for bitwise reading. However, the reading process is significantly prone to error because of the notorious sneak current issue due to the lack of bit-selection devices [26]. Employing transistors as active selectors significantly keeps the sneak current sufficiently low for reliable reading as for the 2T2R-based RCAM design [27]. The CECAM scheme applies to an active array of resistance switches with a voltage-sensing scheme as shown in Fig. 8. In the array, a single unit consists of 2N transistors and 2N resistance switches. A one-transistor and one-resistor (1T1R) unit is placed at a crossing point between each match (horizontal) line and each of the 2N search (vertical) lines. Specifically, the gates of 2N transistors are wired to the 2N search lines, and thus the encoded 2N-digit key determines the channel conductance of the 2N transistors during a searching period. For all transistors, the source is connected to a common plate line which is grounded during searching.

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TABLE 2.	Comparision	with	previous	cam o	lesigns.
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	16T-TCAM [11]	6T2R-TCAM [18]	2T2R-TCAM [16]	2T2R-TCAM [25]	2R-TCAM [23]	4-CECAM with reference to [25]	4-CECAM with reference to [23]
Memory type	SRAM	MTJ*	PCM*	RS*	RS*	RS*	RS*
Reading scheme	Voltage	Voltage	Voltage	Voltage	Current	Voltage	Current
Technology (nm)	65	90	90	130	90	130	90
Word width (bit)	72	32	64	128	64	128	64
Cell area (µm²/bit)	1.69	10.35	0.41	NA (1×)	NA (1×)	NA (0.67×)	NA (0.67×)
Supply voltage (V)	1	1.2	1.2	0.9	0.2	0.9	0.2
Search delay	1.9 ns	0.29 ns	1.9 ns	2 ns	0.5 ps	$2 \text{ ns} + 4/f_{\text{clk}}$	$0.5 \text{ ps} + 4/f_{clk}$

^{*}MTJ, PCM, and RS denote magnetic tunnel junction, phase-change memory, and resistance switch, respectively.

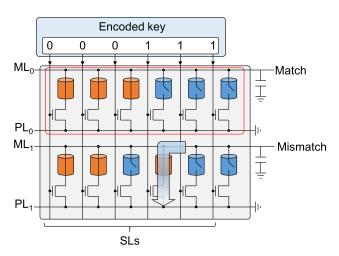


FIGURE 8. Schematic of CECAM with a voltage-reading scheme. The blue arrow in the second row illustrates activated pull-down path.

When searching, the match lines are pre-charged simultaneously. Then, a 2*N*-digit encoded key is applied to the search lines such that 1's and 0's pull the search lines up and down, respectively. When matching *N* 1's in the encoded key to the transistors paired with the *N* HRS switches, the voltage on the match line remains high because none of the pull-down paths are activated. Otherwise, some 1's in the encoded key are inevitably associated with transistors paired with LRS switches, indicating the activation of pull-down paths (Fig. 8). Therefore, the voltage on the pre-charged match line decays rapidly, which is noticed by a sense amplifier as a mismatch. This search process is identical to the 2T2R-based conventional RCAM [25].

Regarding the sense amplifier design for the CECAM, a current- and a voltage-sensing amplifier are suitable for a passive and active array of switches, respectively, as for RCAM. Compared with RCAM, the CECAM does not impose additional requirements on its sense amplifiers, so that previously developed sensing technologies [16], [28], [29] are compatible with the CECAM. In this regard, the CECAM can make full use of previous RCAM technologies given a subtle difference between the CECAM and RCAM. The subtle difference lies in content- and search

key-encoding, which is the key of our present study. Nevertheless, the subtle difference remarkably enhances the content density.

The application domain of the proposed CECAM fully covers other resistance-based NVMs with two-terminal switches, e.g., phase-change memory [14], [15] and magnetic tunnel junction [14], [17], in both active and passive arrays. Moreover, the CECAM concept is compatible with three-terminal NVMs, for instance, ferroelectric transistors [20] and NOR Flash memory.

Table 2 compares the CECAM with previous CAM designs. The 4-CECAM was considered with reference to the 4 kb 1T1R RRAM prototype [25] and simulation results of a 2R-TCAM [23]. The 128 bit word width in [25] allows 16 × (4-CECAM domain), i.e., $N_p = 4$ and $n_p = 16$. According to (2), each match line holds 96 bit contents; instead, the conventional RCAM allows 64 bit contents per match line only. Therefore, the cell area per content bit is approximately 0.67 times that of the conventional RCAM as shown in Table 2. The same holds for the 2R-TCAM with 64 bit word width in [23]. Regretfully, the actual size of the 1T1R RRAM prototype [25] is unavailable so that the cell area per bit for the CECAM is expressed as its area relative to that of the RCAM (0.67). The additional delay in searching due to the encoding of a search key is N_p/f_{clk} , where is f_{clk} clock speed. The cell area per bit and search delay aside, the CECAM is identical to the RCAM.

VI. CONCULSION

A new type of CAM, referred to as CECAM, was proposed to improve the content density in a memory array. The N-CECAM employs a group of 2N resistance switches as a single memory unit with multi-bit (n-bit) capacity, which enhances its content density far beyond that of the conventional RCAM (0.5 bit/switch). For instance, 10-CECAM (N=10; 20 resistance switches) has 17-bit content capacity (n=17) in contrast to the conventional RCAM that needs 34 resistance switches for 17-bit content capacity. The key to the CECAM is an algorithm for n-to-2N encoding and its decoding. The proposed encoding and decoding algorithms were proven to match n-bit search keys to 2N-digit keys bijectively. Additionally, the algorithms are readily

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implemented in digital circuits with a combination table, which results in an encoding (decoding) delay of N clock cycles for the N-CECAM. The proposed CECAM concept is compatible with various NVM-based CAM designs including active and passive RCAM, other two-terminal resistance switch-based CAM, e.g., phase-change memory and magnetic memory, and NVM transistors, e.g., ferroelectric transistor and NOR Flash memory.

APPENDIX

Theorem 1: $E_N: A_t \to B_t$ is a bijective function for $A_t = \left\{0, 1, \dots, \binom{2N}{N} - 1\right\}$ and $B_t = \{b \mid b: 2N\text{-bit binary numbers, each with } N \text{ 1's and } N \text{ 0's}\}.$

Proof: Nonnegative integer a_i is defined as

$$a_{i+1} = a_i - {c_i \choose N-i}$$
 for $0 \le i < N-1$, (3)

and $a_0 = a \ge 0$). c_i satisfies the following inequality:

$$\binom{c_i}{N-i} \le a_i < \binom{c_i+1}{N-i} \quad \text{for } 0 \le i < N.$$
 (4)

Define the number of elements in set
$$X$$
 as $n(X)$.
Lemma 1: $n(A_t) = n(B_t) = \binom{2N}{N}$.
Lemma 2: $c_i > c_{i+1}$ for $0 \le i < N-1$.

Proof: For $a_i = 0$, the only c_i satisfying the inequality in (4) is $c_i = N - i - 1$ that yields $a_{i+1} = 0$ according to (1). From (4), $c_{i+1} = N - i - 2$. Therefore, $c_i > c_{i+1}$. For $a_i > 0$, using (3) and the fact that $a_i < {c_i + 1 \choose N - i}$ in (4), the following inequality is acquired:

$$0 \le a_{i+1} < \begin{pmatrix} c_i + 1 \\ N - i \end{pmatrix} - \begin{pmatrix} c_i \\ N - i \end{pmatrix} = \begin{pmatrix} c_i \\ N - (i+1) \end{pmatrix}. \tag{5}$$

Equation (4) for
$$a_{i+1}$$
 is $\begin{pmatrix} c_{i+1} \\ N - (i+1) \end{pmatrix} \leq a_{i+1} < a_{i+1}$

 $\binom{c_{i+1}+1}{N-(i+1)}$. a_{i+1} should simultaneously satisfy this

equation and (3), which is true if
$$\binom{c_i}{N-(i+1)}$$
 >

$$\binom{c_{i+1}}{N-(i+1)}$$
. Therefore, $c_i > c_{i+1}$.

Consequently, $c_i > c_{i+1}$ holds for nonnegative a_i .

For given a, vector c(a) is defined as c(a) $[c_0, c_1, \ldots, c_{N-1}]$ where the components are sorted in descending order according to Lemma 2. Associating b with c(a) such that '1' is placed on each (c_i+1) th digit of b, and '0's on the other digits, it is proven that c(a) is bijectively mapped to b. If a is also bijectively mapped to c(a), a is eventually proven to be mapped to b in a bijective manner. Also, using Lemma 1 and bijective mapping of c(a) to b, the following equation is acquired:

$$n(\mathbf{A}_t) = n(\mathbf{B}_t) = n(\mathbf{C}) = \begin{pmatrix} 2N \\ N \end{pmatrix}, \tag{6}$$

where $C = \{c \mid c = c(a)\}.$

Lemma 3: if $x \neq y$, then $c(x) \neq c(y)$.

Proof: If Lemma 3 is true, its contraposition (if c(x)) c(y), then x = y is also true. Given (1), $a(= a_0)$ is expressed as

$$a = a_{N-1} + \sum_{i=0}^{N-2} {c_i \choose N-i}.$$
 (7)

Equation (4) for
$$i = N$$
-1 yields $\binom{c_{N-1}}{1} \le a_{N-1} < \binom{c_{N-1}+1}{1}$, i.e., $c_{N-1} \le a_{N-1} < c_{N-1}+1$. Thus, $a_{N-1} = c_{N-1} = \binom{c_{N-1}}{1}$. Therefore, (7) is rewritten by $a = \sum_{i=0}^{N-1} \binom{c_i}{N-i}$. This equation indicates a unique a for a given vector $c(a)$, so that if $c(x) = c(y)$, then $x = y$. Lemma 3 therefore holds true, identifying injective mapping of a to c .

Equation (6) and Lemma 3 identify bijective mapping of a to c. Given the bijective mapping of a to c and c to b, the encoding function E_N is a bijective function.

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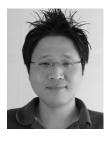
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